

# Talos F200X S/TEM

## Fast chemical analysis in multiple dimensions

The Talos F200X scanning/transmission electron microscope (S/TEM) delivers the fastest, most precise, quantitative characterization of nanomaterials in multiple dimensions. With innovative features designed to increase throughput, precision and ease of use, the Talos F200X S/TEM is ideal for advanced research and analysis across academic, government, and industrial research environments.

### High resolution imaging for better-quality data

The Thermo Scientific™ Talos™ F200X S/TEM combines outstanding high-resolution S/TEM and TEM imaging with industry-leading energy dispersive x-ray spectroscopy (EDS) signal detection, and 3D chemical characterization with compositional mapping. The Thermo Scientific Velox™ S/TEM control software significantly improves imaging with a Smart Scanning engine, four-channel integration based on multiple STEM detectors, and Differential Phase Contrast (DPC) imaging for resolving electro-magnetic structures. Gain high speed and superior accuracy for EDS data processing and quantification applications.

The X-FEG high brightness electron source delivers high total current—up to five times the beam current of a standard Schottky FEG—while keeping the convergence angle small. You gain improved signal-to-noise ratio and exceptional image resolution for STEM, EDS, and high resolution TEM applications. Stability and a long lifecycle enable the X-FEG to deliver superior imaging efficiency.

### See more, faster

Fast TEM imaging on Talos D/TEM supports high-resolution and *in situ* dynamic observations. The Thermo Scientific Ceta 16M™ camera displays a large field of view and captures images at a fast rate of 25 fps, while the piezo stage ensures high sensitivity, drift-free imaging and precise sample navigation, saving time and allowing you to capture more data from each sample.

### Accelerate nanoanalysis for faster answers

The Talos F200X S/TEM includes the Thermo Scientific Super-X™ patented, integrated EDS system with four silicon drift detectors (SDDs) for superior sensitivity and mapping capabilities of up to 105 spectra/sec. Integration with the X-TWIN objective lens maximizes collection efficiency while delivering outstanding output count rates for a given beam current—even for low intensity EDS signals.

### Key Benefits

**Better image data** High throughput STEM imaging with simultaneous, multiple signal detection delivers better contrast for high quality images

**Faster time to chemical composition data** Rapid, precise quantitative EDS analysis reveals nanoscale details

**Space for more** Add application-specific *in situ* sample holders for dynamic experiments



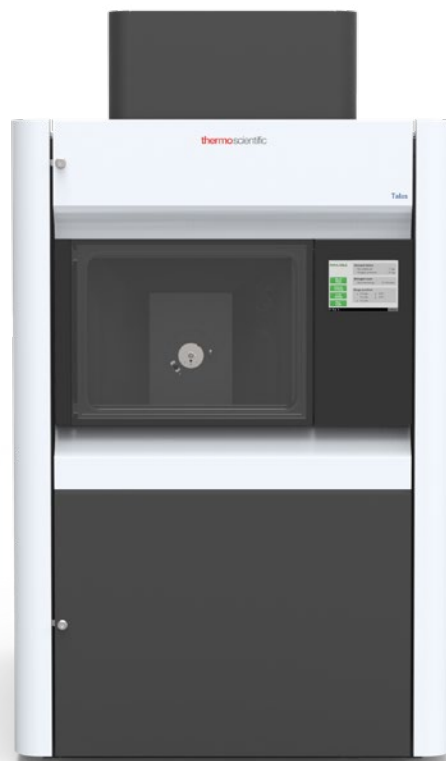
3D EDS tomogram of P-Zn-In nanotubes.  
Sample Courtesy of Dr. Reza Shahbazian Yassar, Michigan Tech University.

## Make research easier

The Talos S/TEM makes imaging and analysis workflows accessible to a broader community of scientists, with a friendly digital user interface and class-leading ergonomics. Fast image acquisition combined with the easy-to-use operating platform allows even less-experience operators to collect results quickly. Implement full remote operation for greater ease of use and enhanced environmental stability. And to assure that productivity is maintained, the Talos S/TEM is equipped with the new Health Monitor that collects key instrument parameters to facilitate remote diagnostics and support.

## Features

- Class-leading optical performance: Constant-power X-TWIN objective lens
- Maximized ease-of-use: Fast, easy operation switching, fits for multi-user environments
- Ultra-stable platform: Constant power objective lens, piezo stage, robust system enclosure, and remote operation ensure maximum stability
- SmartCam camera: Digital search-and-view camera improves the handling of all applications and allows daylight operation
- Fully integrated fast detector: Ceta 16M pixel CMOS camera provides large field of view and high read-out speed (25 fps @ 512 × 512)
- Full remote operation: Automatic aperture system in combination with the Ceta and SmartCam camera supports full remote operation
- Extended analytical capabilities: the Talos S/TEM extends analytical capabilities to 3D volumes using EDS tomography



## Installations Requirements

Refer to preinstall guide for detailed data.

### Talos F200X

Brightness of X-FEG	$1.8 \times 10^9$ A/cm <sup>2</sup> srad (@200kV)
Total beam current	> 50nA
Probe current	1.5 nA @ 1 nm probe (200 kV)
Super-X EDS system	4 SDD symmetric design, windowless, shutter-protected
Energy resolution	≤136 eV for Mn-K $\alpha$ and 10 kcps (output)
Fast EDS mapping	Pixel dwell times down to 10 $\mu$ s

### X-Twin

STEM HAADF resolution	0.16 nm
EDX solid angle	0.9 srad
TEM Information limit	0.12 nm
Maximum diffraction angle	24°
Maximum tilt angle with double tilt holder	±35° alpha tilt / ±30° beta tilt
Maximum goniometer (stage) tilt angle	±90°

Find out more at [thermofisher.com/EM-Sales](http://thermofisher.com/EM-Sales)